


<b>Search Notes</b> 	<b>Application/Control No.</b> 10661503	<b>Applicant(s)/Patent Under Reexamination</b> HIKAWA ET AL.
	<b>Examiner</b> PHILIP C LEE	<b>Art Unit</b> 2452

SEARCHED			
Class	Subclass	Date	Examiner
709	106,224	7/18/08	/pl/
707	10	7/18/08	/pl/
717	102	7/18/08	/pl/

SEARCH NOTES			
Search Notes		Date	Examiner
keywords search in EAST		7/18/08	/pl/
keywords search in 709/106,224; 707/10; 717/102 in EAST		7/18/08	/pl/
keywords search in EAST		2/25/09	/pl/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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